



# 3.3V CMOS OCTAL D REGISTER (3-STATE)

IDT74FCT3574/A

## FEATURES:

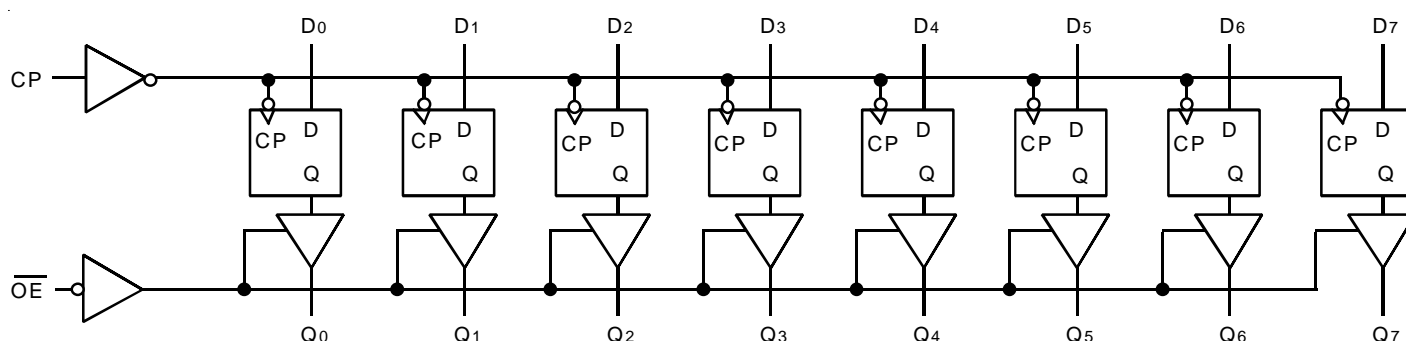
- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- $V_{CC} = 3.3V \pm 0.3V$ , Normal Range
- $V_{CC} = 2.7V$  to  $3.6V$ , Extended Range
- CMOS power levels ( $0.4\mu W$  typ. static)
- Rail-to-Rail output swing for increased noise margin
- Available in QSOP, SOIC, and TSSOP packages

## DESCRIPTION:

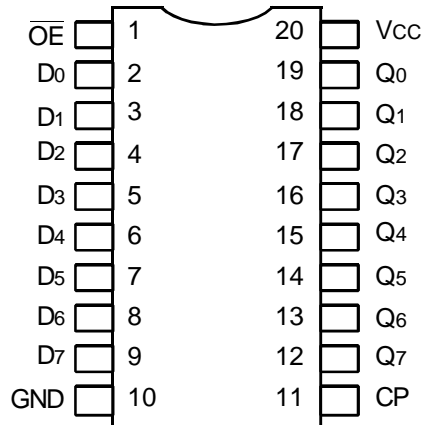
The FCT3574/A are 8-bit registers built using an advanced dual metal CMOS technology. These registers consist of eight D-type flip-flops with a buffered common clock and buffered 3-state output control. When the  $\overline{OE}$  input is low, the eight outputs are enabled. When the  $\overline{OE}$  input is high, the outputs are in the high-impedance state.

Input data meeting the set-up and hold time requirements of the D inputs is transferred to the Q outputs on the low-to-high transition of the clock input.

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



QSOP/ SOIC/ TSSOP  
TOP VIEW

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Description	Max	Unit
V <sub>TERM</sub> <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
V <sub>TERM</sub> <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to +7	V
V <sub>TERM</sub> <sup>(4)</sup>	Terminal Voltage with Respect to GND	-0.5 to V <sub>CC</sub> +0.5	V
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
I <sub>OUT</sub>	DC Output Current	-60 to +60	mA

### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V<sub>CC</sub> terminals.
- Input terminals.
- Outputs and I/O terminals.

## CAPACITANCE (T<sub>A</sub> = +25°C, F = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	3.5	6	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	4	8	pF

### NOTE:

- This parameter is measured at characterization but not tested.

## PIN DESCRIPTION

Pin Names	Description
Dx	D Flip-Flop Data Inputs
CP	Clock Pulse for the register. Enters data on LOW-to-HIGH transition.
$\overline{OE}$	3-State Output Enable Input (Active LOW)
Qx	3-State Outputs

## FUNCTION TABLE<sup>(1)</sup>

Function	Inputs			Outputs
	$\overline{OE}$	CP	Dx	Qx
HI-Z	H	L	X	Z
	H	H	X	Z
LOAD REGISTER	L	↑	L	L
	L	↑	H	H
	H	↑	L	Z
	H	↑	H	Z

### NOTE:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care  
Z = High Impedance  
NC = No Change  
↑ = LOW-to-HIGH transition

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 2.7\text{V}$  to  $3.6\text{V}$

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit	
V <sub>IH</sub>	Input HIGH Level (Input pins)	Guaranteed Logic HIGH Level		2	—	5.5	V	
	Input HIGH Level (I/O pins)			2	—	V <sub>CC</sub> +0.5		
V <sub>IL</sub>	Input LOW Level (Input and I/O pins)	Guaranteed Logic LOW Level		-0.5	—	0.8	V	
I <sub>IH</sub>	Input HIGH Current (Input pins)	V <sub>CC</sub> = Max.	V <sub>I</sub> = 5.5V	—	—	±1	μA	
	Input HIGH Current (I/O pins)		V <sub>I</sub> = V <sub>CC</sub>	—	—	±1		
I <sub>IL</sub>	Input LOW Current (Input pins)		V <sub>I</sub> = GND	—	—	±1		
	Input LOW Current (I/O pins)		V <sub>I</sub> = GND	—	—	±1		
I <sub>OZH</sub>	High Impedance Output Current (3-State Output pins)	V <sub>CC</sub> = Max.	V <sub>O</sub> = V <sub>CC</sub>	—	—	±1	μA	
			V <sub>O</sub> = GND	—	—	±1		
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = Min., I <sub>IN</sub> = -18mA		—	-0.7	-1.2	V	
I <sub>ODH</sub>	Output HIGH Current	V <sub>CC</sub> = 3.3V, V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> , V <sub>O</sub> = 1.5V <sup>(3)</sup>		-36	-60	-110	mA	
I <sub>ODL</sub>	Output LOW Current	V <sub>CC</sub> = 3.3V, V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> , V <sub>O</sub> = 1.5V <sup>(3)</sup>		50	90	200	mA	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min.	I <sub>OH</sub> = -0.1mA	V <sub>CC</sub> -0.2	—	—	V	
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -3mA	2.4	3	—		
			V <sub>CC</sub> = 3V	I <sub>OH</sub> = -8mA	2.4 <sup>(5)</sup>	3		—
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min.	I <sub>OL</sub> = 0.1mA	—	—	0.2	V	
			V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 16mA	—	0.2		0.4
				I <sub>OL</sub> = 24mA	—	0.3		0.55
		V <sub>CC</sub> = 3V	I <sub>OL</sub> = 24mA	—	0.3	0.5		
I <sub>OS</sub>	Short Circuit Current <sup>(4)</sup>	V <sub>CC</sub> = Max., V <sub>O</sub> = GND <sup>(3)</sup>		-60	-135	-240	mA	
V <sub>H</sub>	Input Hysteresis	—		—	150	—	mV	
I <sub>CCL</sub> I <sub>CCH</sub> I <sub>CCZ</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = Max., V <sub>IN</sub> = GND or V <sub>CC</sub>		—	0.1	10	μA	

### NOTES:

- For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient and maximum loading.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- This parameter is guaranteed but not tested.
- V<sub>OH</sub> = V<sub>CC</sub> - 0.6V at rated current.

## POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = Max.	V <sub>IN</sub> = V <sub>CC</sub> - 0.6V	—	2	30	μA
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>(4)</sup>	V <sub>CC</sub> = Max. Outputs Open $\overline{OE}$ = GND One Input Toggling 50% Duty Cycle	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND	—	60	85	μA/ MHz
I <sub>C</sub>	Total Power Supply Current <sup>(6)</sup>	V <sub>CC</sub> = Max. Outputs Open f <sub>CP</sub> = 10MHz 50% Duty Cycle $\overline{OE}$ = GND f <sub>i</sub> = 5MHz One Bit Toggling	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND	—	0.6	0.9	mA
			V <sub>IN</sub> = V <sub>CC</sub> - 0.6V V <sub>IN</sub> = GND	—	0.6	0.9	
		V <sub>CC</sub> = Max. Outputs Open f <sub>CP</sub> = 10MHz 50% Duty Cycle $\overline{OE}$ = GND f <sub>i</sub> = 2.5MHz Eight Bits Toggling	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND	—	1.5	2.2 <sup>(5)</sup>	
			V <sub>IN</sub> = V <sub>CC</sub> - 0.6V V <sub>IN</sub> = GND	—	1.5	2.3 <sup>(5)</sup>	

### NOTES:

- For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient.
- Per TTL driven input. All other inputs at V<sub>CC</sub> or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of ΔI<sub>CC</sub> formula. These limits are guaranteed but not tested.
- I<sub>C</sub> = I<sub>QUIESCENT</sub> + I<sub>INPUTS</sub> + I<sub>DYNAMIC</sub>  
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP} N_{CP} / 2 + f_i N_i)$   
 I<sub>CC</sub> = Quiescent Current (I<sub>CC</sub>, I<sub>CCH</sub>, and I<sub>CCZ</sub>)  
 ΔI<sub>CC</sub> = Power Supply Current for a TTL High Input  
 D<sub>H</sub> = Duty Cycle for TTL Inputs High  
 N<sub>T</sub> = Number of TTL Inputs at D<sub>H</sub>  
 I<sub>CCD</sub> = Dynamic Current caused by an Input Transition Pair (HLH or LHL)  
 f<sub>CP</sub> = Clock Frequency for register devices (zero for non-register devices)  
 N<sub>CP</sub> = Number of clock inputs at f<sub>CP</sub>  
 f<sub>i</sub> = Input Frequency  
 N<sub>i</sub> = Number of Inputs at f<sub>i</sub>

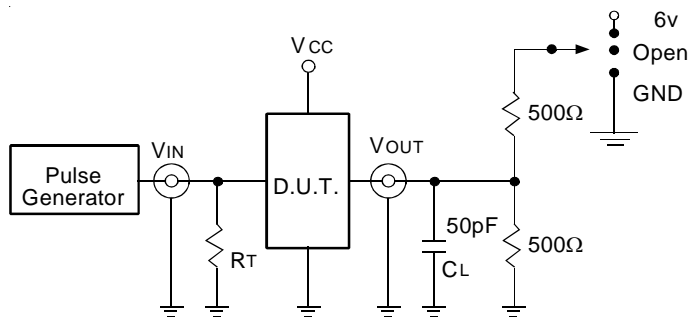
## SWITCHING CHARACTERISTICS OVER OPERATING RANGE<sup>(1)</sup>

Symbol	Parameter	Condition <sup>(2)</sup>	74FCT3574		74FCT3574A		Unit
			Min. <sup>(3)</sup>	Max.	Min. <sup>(3)</sup>	Max.	
t <sub>PLH</sub>	Propagation Delay	C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω	2	10	2	6.5	ns
t <sub>PHL</sub>	CP to Qx						
t <sub>PZH</sub>	Output Enable Time		1.5	12.5	1.5	6.5	ns
t <sub>PZL</sub>							
t <sub>PHZ</sub>	Output Disable Time		1.5	8	1.5	5.5	ns
t <sub>PLZ</sub>							
t <sub>SU</sub>	Set-up Time HIGH or LOW, Dx to CP		2	—	2	—	ns
t <sub>H</sub>	Hold Time HIGH or LOW, Dx to CP		1.5	—	1.5	—	
t <sub>W</sub>	CP Pulse Width HIGH or LOW	7	—	5	—	ns	

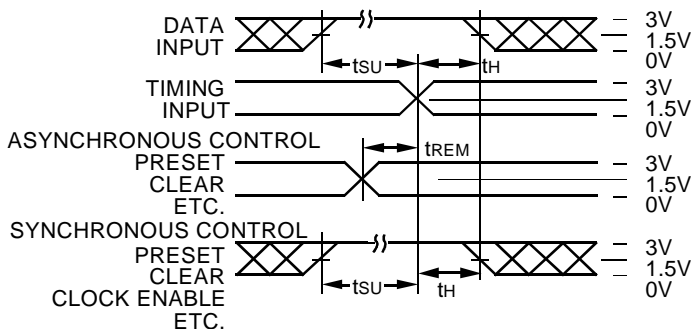
### NOTES:

- Propagation Delays and Enable/Disable times are with V<sub>CC</sub> = 3.3V ±0.3V, Normal Range. For V<sub>CC</sub> = 2.7V to 3.6V, Extended Range, all Propagation Delays and Enable/Disable times should be degraded by 20%.
- See test circuit and waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.

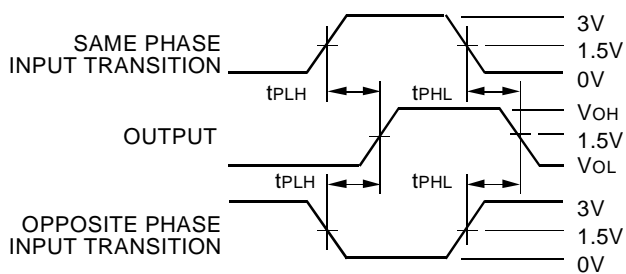
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-Up, Hold, and Release Times



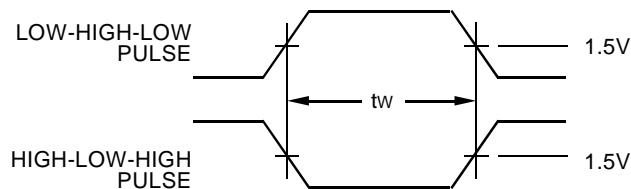
Propagation Delay

SWITCH POSITION

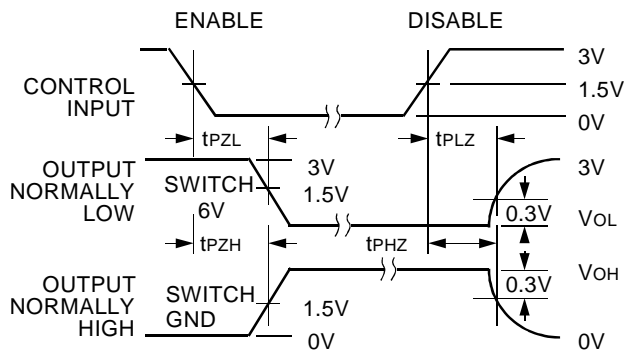
Test	Switch
Open Drain Disable Low Enable Low	6V
Disable High Enable High	GND
All Other Tests	Open

DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.  
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.



Pulse Width

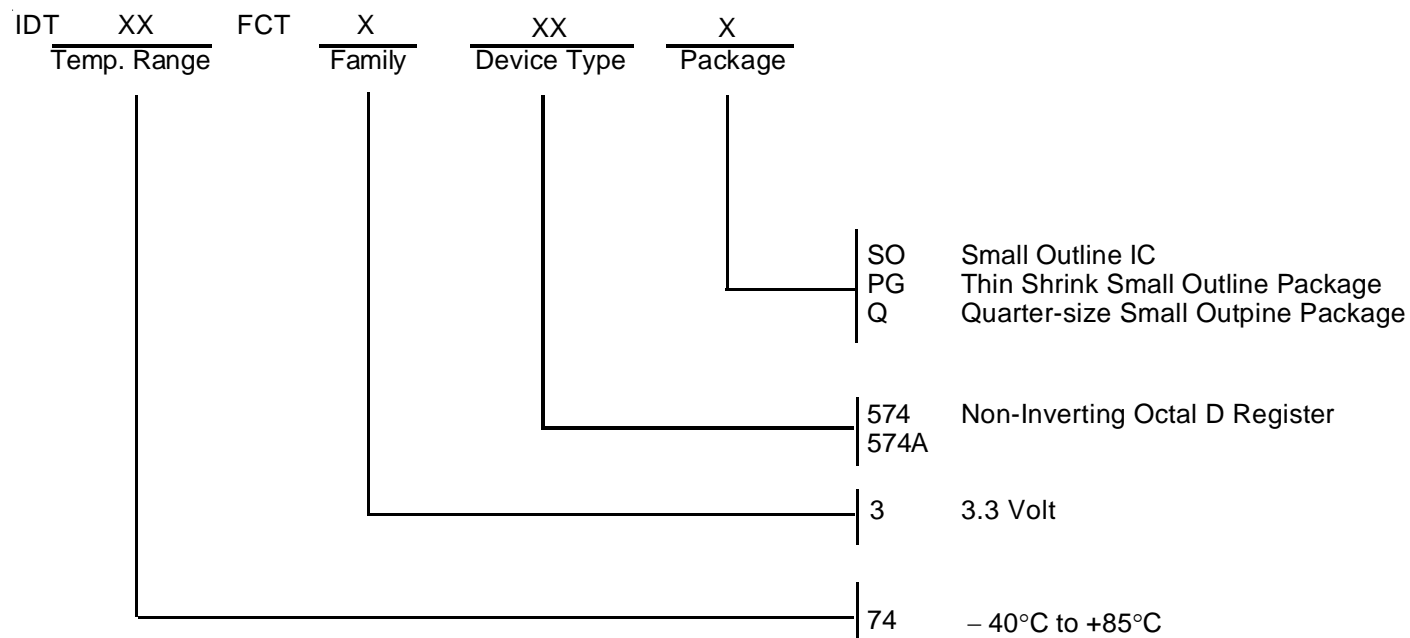


Enable and Disable Times

NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; tr ≤ 2.5ns; tr ≤ 2.5ns.
3. If Vcc is below 3V, input voltage swings should be adjusted not to exceed Vcc.

## ORDERING INFORMATION



**CORPORATE HEADQUARTERS**  
2975 Stender Way  
Santa Clara, CA 95054

**for SALES:**  
800-345-7015 or 408-727-6116  
fax: 408-492-8674  
www.idt.com

**for Tech Support:**  
logichelp@idt.com  
(408) 654-6459